

Form PTO 1449 U.S. Department of Commerce Patent and Trademark Office Information Disclosure Statement by Applicant	ATTY. DOCKET NUMBER	SERIAL NUMBER
	TSUT.0028	To be assigned
	APPLICANT	
	MIRAKAMI et al.	
	FILING DATE	GROUP
	Concurrently herewith	

U.S. Patent Documents

Examiner Initial		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
WLL	**	5,591,681	1/7/97	Wristers et al			6/3/94
WLL	**	6,235,590	5/22/01	Daniel et al			12/18/98
WLL	**	6,258,673	7/10/01	Houlihan et al			12/22/99
WLL	**	6,168,980	1/2/01	Yamazaki et al			9/26/96
WLL	**	6,037,639	3/14/00	Ahmad			6/9/97
WLL	**	5,554,871	9/10/96	Yamashita et al			6/7/95
WLL	**	6,232,244	5/15/01	Ibok			5/1/00
WLL	**	6,051,510	4/18/00	Fulford, Jr. et al			5/2/97
WLL	**	5,702,988	12/30/97	Liang			5/2/96
WLL	**	5,629,221	5/13/97	Chao et al			11/24/95
WLL	**	5,464,783	11/7/95	Kim et al			2/2/95
WLL	**	4,554,726	11/26/85	Hellenius et al			4/17/84

Foreign Patent Documents

Examiner Initial		DOCUMENT NUMBER	FILING DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
							YES	No

Other Documents (Including Author, Title, Date Pertinent Pages, Etc.)

WLL	*	N. Kimizuka, T. Yamamoto, T. Mogami, K. Yamaguchi, K. Imai and T. Horiuchi, "the Impact of Bias Temperature Instability for Direct-Tunneling Ultra-thin GTE Oxide on MOSFET Scaling", 1999 Symposium on VLSI Technology Digest of Technical papers, pp. 73-74				
<table border="1"> <tr> <td>EXAMINER</td> <td>DATE CONSIDERED</td> </tr> <tr> <td>WLL L. Liang</td> <td>5/24/05</td> </tr> </table>			EXAMINER	DATE CONSIDERED	WLL L. Liang	5/24/05
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WLL L. Liang	5/24/05					
<p>Examiner: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; draw a line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant</p>						

PTO 1449

- * Filed by Applicant in Parent
- ** Cited by Examiner in Parent